

<b>Notice of References Cited</b>	Application/Control No. 10/798,577	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,882,595	11-1989	Trueba et al.	347/85
	C	US-4,847,630	07-1989	Bhaskar et al.	347/63
	D	US-5,685,491	11-1997	Marks et al.	239/533.12
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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